

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SHIDLA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,916,696 A	04-1990	Funakubo, Nobuo	714/11
*	B	US-5,195,101 A	03-1993	Guenthner et al.	714/49
*	C	US-5,202,975 A	04-1993	Rasbold et al.	717/151
*	D	US-5,732,209 A	03-1998	Vigil et al.	714/30
*	E	US-5,819,088 A	10-1998	Reinders, James R.	717/149
*	F	US-5,835,776 A	11-1998	Tirumalai et al.	717/161
*	G	US-6,289,300 B1	09-2001	Brannick et al.	703/28
*	H	US-2002/0038418 A1	03-2002	Shimamura, Akimitsu	712/245
*	I	US-6,408,377 B2	06-2002	Munson, Kenneth K.	712/215
*	J	US-6,434,712 B1	08-2002	Urban et al.	714/12
*	K	US-6,553,530 B1	04-2003	Kim, Heon-cheol	714/738
*	L	US-6,625,688 B1	09-2003	Fruehling et al.	711/109
*	M	US-6,640,313 B1	10-2003	Quach, Nhon	714/10

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,396,618 A	03-1995	Fukui et al.	714/30
*	B	US-5,530,804 A	06-1996	Edgington et al.	714/30
*	C	US-5,640,508 A	06-1997	Fujiwara et al.	714/30
*	D	US-5,838,692 A	11-1998	Tobin, Paul G.	714/724
*	E	US-5,838,897 A	11-1998	Bluhm et al.	714/30
*	F	US-6,134,675 A	10-2000	Raina, Rajesh	714/37
*	G	US-6,385,755 B1	05-2002	Shimomura et al.	714/819
*	H	US-2004/0039967 A1	02-2004	Park, Jin-Kwon	714/30
*	I	US-2005/0055683 A1	03-2005	Shidla et al.	717/161
*	J	US-2005/0055608 A1	03-2005	Shidla et al.	714/025
*	K	US-2005/0055674 A1	03-2005	Shidla et al.	717/131
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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